

FORM PTO-1449 SAMUELS, GAUTHIER & STEVENS LLP (Rev. 5/92) 225 Franklin Street, Boston, MA 02110 Telephone: (617) 426-9180	MIT.10086 ATTORNEY DOCKET NO. APPLICANT: Kimerling et al. FILING DATE: 12/11/2003	10/733,977 SERIAL NO. GROUP: 2827 2883 EXAMINER: Unknown Derek Dupuis
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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

JUL 09 2004

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
DLD	AA 5,107,316	04/21/1992	Jelley et al.			12/28/1989
	AB					
	AC					

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
DLD	AD 62011810	01/20/1987	JP			YES (Abstract Only)
DLD	AE 923335	10/23/1982	SU			YES (Abstract Only)
	AF					

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER INITIAL		
DLD	AG	"Development and Application of flux-paste for laser welding of aluminum alloys," Cretteur et al. <i>Welding International</i> . 2000.
DLD	AH	"Theoretical study on the coupling of two-dimensional Gaussian beam to a dielectric slab waveguide," Nishimura et al. <i>Transactions of the Institute of Electronics and Communication Engineers of Japan</i> . May 1984.
DLD	AI	"Fresnel-like behavior of guided waves," Shen et al. <i>Journal of Optical Society of America</i> . November 1987.
DLD	AJ	"Ultrafast photon drag detector for intersubband spectroscopy," Sigg et al. <i>Superlattices and Microstructures</i> . 1996. Vol. 19, No. 2.
DLD	AK	"Critical-Incidence Coupling to intersubband Excitations," Keilmann et al. <i>Solid State Communications</i> . 1994. Vol. 92, No. 3.
DLD	AL	"Efficient high-speed near-infrared Ge photodetectors integrated on Si Substrates," Colace et al. <i>Applied Physics Letters</i> . 2000. Vol. 76, No. 10.
DLD	AM	"Optoelectronic Conversion through 850nm Band Single Mode Si ₃ N ₄ Photonic Waveguides for Si-On-Chip Integration," Matsuura et al. <i>Device Research Conference, Conference Proceedings</i> . Santa Barbara, CA. June 2002.
DLD	AN	"Near and mid infrared silicon/germanium based photodetection," Presting. <i>Thin Solid Films</i> . 1998. Vol. 321.

EXAMINER *DL 2*

DATE CONSIDERED *9-15-2004*

EXAMINER:

Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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MIT.10086
ATTORNEY DOCKET NO.

APPLICANT: Kimerling et al.

FILING DATE: ~~March 11~~
12/11/2003

~~Unknown~~ 10/733977
SERIAL NO.

GROUP: ~~Unknown~~ 2883

EXAMINER: ~~Unknown~~
Deek Dupuis

U.S. PATENT DOCUMENTS

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	AA						
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	AI						

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	AJ						
	AK						
	AL						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER INITIAL		
DLD	AM	"FDTD Analysis of a Polarization Conversion Waveguide with a Single Sloped Sidewall," Yamauchi et al. <i>Optical Society of America</i> . June 2003.
	AN	
	AO	

EXAMINER *Del 2.8*

DATE CONSIDERED 9-15-2004

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.